# Abstracts

## Novel method for determination of junction-FET access resistances

*K. Osgood and A. Parker. "Novel method for determination of junction-FET access resistances." 1997 MTT-S International Microwave Symposium Digest 2. (1997 Vol. II [MWSYM]): 873-876.*

A new method for extracting JFET access resistances, which does not need to consider the intrinsic channel resistance of the device, is presented. The method uses an impedance data set measured over a range of bias points. The data set is reduced to those points with reciprocal impedance matrices and appropriate bias conditions. The extraction procedure is ideal for automated device characterisation.

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